Search Notes



Appl	icati	ion/	Con	trol	No.	

10551039

Applicant(s)/Patent Under Reexamination FUJITA ET AL.

Examiner

Art Unit

NIKHIL SRIRAMAN

3664

SEARCHED				
Class	Subclass	Date	Examiner	
700	245, 248, 249, 250, 253	12/20/2008	NS	

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Marc McDieunel	12/20/2008	
Assignee search on East, Inventor search on eDan		
NPL, including IEEE databases searched (see attached history)		
Reviewed submitted IDS references	7/12/2009	
Updated search in light of claim amendments; consulted with Examiner Joge Peche and Examiner Kyung Kim on search strategy on claim interpretation	12/19/2009	
Consulted with Examiner Lin Olsen on apparatus claim construction in light of removal of "means plus function" language in Applicant's amendment	6/25/2010	

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

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